

Notic of Referenc s Cited	Application/Control No. 09/406,663	Applicant(s)/Patent Under Reexamination KNEBEL ET AL.	
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	C	US-5,251,159 ✓	10-1993	Rowson, James A.	703/14
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	K	US-			
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